# MERICAN **AICROSEMICONDUCTOR**

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# nottky Barrier Chip

# Mechanical Specifications





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#### Notes:

1. Dimension tolerance ±0.03 (1).

2. Top contact is anode

3. All contact metallization is gold.

#### Features

- Thermocompression / thermosonically bondable
- Gold metallization
- Silicon Nitride Passivation
- Uniform Electrical Characteristics
- **Batch Matched Versions** Available
- Planar Construction
- Ideal for Hybrid Integrated Circuits

## Abstract

These Schottky chips are designed for hybrid applications at DC through K-band frequencies. The passivated planar construction of these Schottky chips provides a wide temperature range capability combined with broad bandwidth performance. A variety of chips are provided which are optimized for various analog and digital applications. Typical applications of Schottky chips are mixing, detecting, switching, gating, sampling, and wave shaping.

HSMS-0001 is specifically designed for analog and digital requiring hybrid applications thermosonic or thermocompression bonding techniques. The large bonding pad and offset junction allows easy bonding. The top metallization is a layer of gold deposited on adhesive metal layers for a tarnish-free surface that allows either thermosonic or thermocompression bonding techniques. The bottom metallization is also gold, suitable for epoxy or extectic die attach methods.

### Maximum Ratings and Electrical Characteristics @ Ta = 25°C unless otherwise specified

Description	Value / Range	Unit
Junction Operating and Storage Temperature	-65 to +200	°C
Power Dissipation @ $T_A = 25^{\circ}C$ Measured in an infinite heat sink derated linearly to zero at maximum rated temperature	250	mW
I <sub>F</sub> max (1 μs pulse) Operation in excess of any one of these conditions may result in permanent damage	1	А

Description	Abr.	Value / Range	Unit	Test Condition
Minimum Breakdown Voltage	$V_{\text{BR}}$	70	V	I <sub>R</sub> = 10μΑ
Maximum Forward Voltage	$V_{F}$	410	mV	$I_F = 1mA$
Maximum Forward Voltage	$V_{F}$	1.0	V	
	@ I <sub>F</sub>	15	mV	
Maximum Capacitance	Ст	1.72	pF	$V_R = 0V$ , f = 1.0MHz
Maximum Reverse Leakage Current	I <sub>R</sub>	200	nA	
	@ V <sub>R</sub>	50	V	

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